

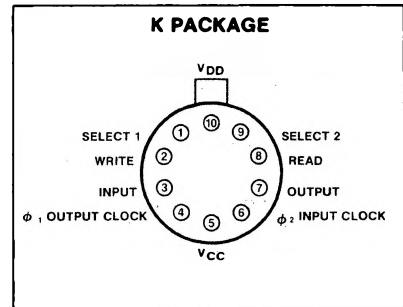
**DESCRIPTION**

The 2505 512-bit and the 2512 1024-bit recirculating dynamic shift registers consist of enhancement mode p-channel MOS devices integrated on a single monolithic chip. Internal recirculation logic plus write and read controls, together with 2 chip select controls are included on the chip.

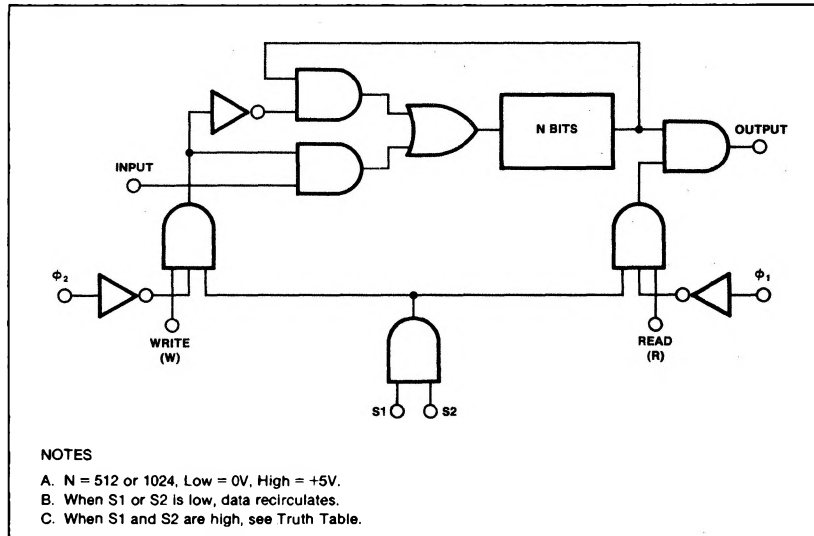
**TRUTH TABLE**

WRITE	READ	FUNCTION
0	0	Recirculate, Output is '0'
0	1	Recirculate, Output is data
1	0	Write mode, Output is '0'
1	1	Read/write, Output is data

**PIN CONFIGURATION**



**BLOCK DIAGRAM**



**ABSOLUTE MAXIMUM RATINGS<sup>1</sup>**

PARAMETER	RATING	UNIT
T <sub>A</sub> Operating	0 to 70	°C
T <sub>STG</sub> Storage	-65 to 150	
P <sub>D</sub> Power dissipation at T <sub>A</sub> > 70°C <sup>2</sup>	535	mW
Data and clock input voltages and supply voltages with respect to V <sub>CC</sub>	0.3 to -20	V

**DC ELECTRICAL CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ ,  $V_{CC} = 5\text{V} \pm 5\%$ ,  $V_{DD} = -5\text{V} \pm 5\%$  unless otherwise specified.

PARAMETER	TEST CONDITIONS	2505			2512			UNIT
		Min	Typ	Max	Min	Typ	Max	
Input voltage <sup>3</sup> V <sub>IL</sub> Low V <sub>IH</sub> High V <sub>ILC</sub> Clock low V <sub>IHC</sub> Clock high		-5.0		0.6	-5.0		0.6	V
		3.4		5.3	3.4		5.3	
		-12.0		-10.0	-12.0		-10.0	
		4.0		5.3	4.0		5.3	
Output voltage V <sub>OL</sub> Low V <sub>OH1</sub> High, driving 1 TTL load V <sub>OH2</sub> High, driving MOS	R <sub>L</sub> = 3.0K, 1 TTL load (I <sub>L</sub> = 1.6mA) <sup>4</sup>		-1.0			-1.0		V
	R <sub>L</sub> = 3.0K, 1 TTL load (I <sub>L</sub> = 100 $\mu$ A)	2.4	3.5		2.4	3.5		
	R <sub>L</sub> = 5.6K, C <sub>L</sub> = 10pF	3.6	4.0		3.6	4.0		
I <sub>LI</sub> Input load current	V <sub>IN</sub> = 5.5V, T <sub>A</sub> = 25°C		10	500		10	500	nA
Leakage current I <sub>LO</sub> Output I <sub>LC</sub> Clock	T <sub>A</sub> = 25°C V $\phi$ 1 = V $\phi$ 2 = -12V, V <sub>DD</sub> = -5V, V <sub>OUT</sub> = -5.5V V <sub>ILC</sub> = -12V		10	1000		10	1000	nA
			10	1000		10	1000	
I <sub>DD</sub> Supply current	Continuous operation, $\phi$ pW = 150ns, 1MHz, V <sub>ILC</sub> = -12V, T <sub>A</sub> = 25°C, V <sub>DD</sub> = -5.5V		15	25		25	35	mA
Capacitance C <sub>IN</sub> Input C <sub>OUT</sub> Output C $\phi$ Clock	1 MHz, V <sub>AC</sub> = 25mV p-p V <sub>I</sub> = V <sub>CC</sub> V <sub>O</sub> = V <sub>CC</sub> V $\phi$ = V <sub>CC</sub>			5			5	pF
				5			5	
				50			100	

**AC ELECTRICAL CHARACTERISTICS**  $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5\text{V}^3$ ,  $V_{DD} = -5\text{V} \pm 5\%$ ,  $V_{ILC} = -11\text{V}$

PARAMETER	TO	FROM	TEST CONDITIONS	LIMITS			UNIT
				Min	Typ	Max	
Freq. Clock data rep rate			W = R = V <sub>CC</sub>	.0005	3	2.5	MHz
t $\phi$ PW Clock pulse width				180			ns
t $\phi$ D Clock pulse delay				10			ns
t <sub>r</sub> , t <sub>f</sub> Clock pulse transition						1	$\mu$ s
t <sub>DW</sub> Setup and hold time t <sub>DH</sub> Setup time Hold time	Input clock Data in	Data in		150			ns
		Input clock		10			
t <sub>A+</sub> , t <sub>A-</sub> Delay time	Data out	Clock				100	ns
t <sub>R-</sub> , t <sub>CS-</sub> , t <sub>w-</sub> t <sub>R+</sub> , t <sub>CS+</sub> , t <sub>w+</sub> Clock to read or chip select or write timing				0			ns
				0			

**NOTES**

- Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W junction to ambient.
- Guaranteed input levels are stated for worst case conditions including a  $\pm 5\%$  variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.
- V<sub>OL</sub> is a function of the input characteristics of the driven TTL/DTL gate I<sub>O</sub>, and V<sub>CLAMP</sub> and the value of the pull-down resistor (R<sub>L</sub>).
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless otherwise specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at +25°C and typical supply voltage.

**TIMING DIAGRAM**

